# EEPROM, Serial, 4-Kb I<sup>2</sup>C, Low Voltage Automotive Grade 1

## NV24C04LV

### Description

The NV24C04LV are 4–Kb CMOS Serial EEPROM devices that operate at a minimum 1.7 V supply voltage. They are organized internally as 16 and 128 pages respectively of 16 bytes each. All devices support the Standard (100 kHz), Fast (400 kHz) and Fast–Plus (1 MHz) I<sup>2</sup>C protocol.

Data is written by providing a starting address, then loading 1 to 16 contiguous bytes into a Page Write Buffer, and then writing all data to non-volatile memory in one internal write cycle. Data is read by providing a starting address and then shifting out data serially while automatically incrementing the internal address count.

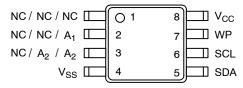
External address pins make it possible to address up to four NV24C04 device on the same bus.

#### **Features**

- Automotive AEC-Q100 Grade 1 (-40°C to +125°C) Qualified
- Supports Standard, Fast and Fast–Plus I<sup>2</sup>C Protocol
- 1.7 V to 5.5 V Supply Voltage Range
- 16-Byte Page Write Buffer
- Fast Write Time (4 ms max)
- Hardware Write Protection for Entire Memory
- Schmitt Triggers and Noise Suppression Filters on I<sup>2</sup>C Bus Inputs (SCL and SDA)
- Low power CMOS Technology
- More than 1,000,000 Program/Erase Cycles
- 100 Year Data Retention
- Automotive Grade 1 Temperature Range
- SOIC, TSSOP, US 8-Lead, TSOP-5 Lead and Wettable Flank UDFN 8-pad Packages
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

### PIN CONFIGURATION (SOIC-8,US-8,UNFN-8,TSSOP-8)

#### NV24C04





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US8 U SUFFIX CASE 493



TSSOP-8 DT SUFFIX CASE 948AL



TSOP-5 SN SUFFIX CASE 483



UDFN-8 MUW3 SUFFIX CASE 517DH

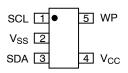


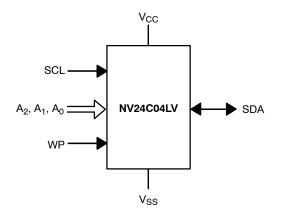
SOIC8 DW SUFFIX CASE 751BD

#### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information in the package dimensions section on page 14 of this data sheet.

### PIN CONFIGURATION (TSOP-5)





**Table 1. PIN FUNCTION** 

Pin Name	Function	
A0, A1, A2	Device Address Input	
SDA	Serial Data Input/Output	
SCL	Serial Clock Input	
WP	Write Protect Input	
V <sub>CC</sub>	Power Supply	
V <sub>SS</sub>	Ground	
NC	No Connect	

Figure 1. Functional Symbol

### **Table 2. ABSOLUTE MAXIMUM RATINGS**

Parameters	Ratings	Units
Storage Temperature	−65 to +150	°C
Voltage on any pin with respect to Ground (Note 1)	-0.5 to +6.5	V

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

### **Table 3. RELIABILITY CHARACTERISTICS**

Symbol	Parameter	Min	Units
N <sub>END</sub> (Note 2)	Endurance	1,000,000	Write Cycles (Note 3)
T <sub>DR</sub> (Note 2)	Data Retention	100	Years

<sup>2.</sup> T<sub>A</sub> = 25°C

Table 4. D.C. OPERATING CHARACTERISTICS ( $V_{CC}$  = 1.7 V to 5.5 V,  $T_A$  = -40°C to +125°C, unless otherwise specified.\*)

Symbol	Parameter	Test Condit	ions	Min	Max	Units
I <sub>CCR</sub>	Read Current	Read, f <sub>SCL</sub> = 1 MHz			0.3	mA
I <sub>CCW</sub>	Write Current	Write			0.5	mA
I <sub>SB</sub>	Standby Current	All I/O Pins at GND or V <sub>CC</sub>	$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$		1	μΑ
			$T_A = -40^{\circ}\text{C to } +125^{\circ}\text{C}$		2	
ΙL	I/O Pin Leakage	Pin at GND or V <sub>CC</sub>			2	μΑ
V <sub>IL1</sub>	Input Low Voltage	$2.2 \text{ V} \le \text{V}_{CC} \le 5.5 \text{ V}$		-0.5	0.3 V <sub>CC</sub>	V
V <sub>IL2</sub>	Input Low Voltage	1.7 V ≤ V <sub>CC</sub> < 2.2 V		-0.5	0.2 V <sub>CC</sub>	V
V <sub>IH1</sub>	Input High Voltage	$2.2 \text{ V} \le \text{V}_{CC} \le 5.5 \text{ V}$		0.7 V <sub>CC</sub>	V <sub>CC</sub> + 0.5	V
V <sub>IH2</sub>	Input High Voltage	1.7 V ≤ V <sub>CC</sub> < 2.2 V		0.8 V <sub>CC</sub>	V <sub>CC</sub> + 0.5	V
V <sub>OL1</sub>	Output Low Voltage	$V_{CC} \ge 2.2 \text{ V}, I_{OL} = 6.0 \text{ mA}$			0.4	V
$V_{OL2}$	Output Low Voltage	$V_{CC}$ < 2.2 V, $I_{OL}$ = 2.0 mA			0.2	V

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

During input transitions, voltage undershoot on any pin should not exceed –1 V for more than 20 ns. Voltage overshoot on pins A<sub>0</sub>, A<sub>1</sub>, A<sub>2</sub> and WP should not exceed V<sub>CC</sub> + 1 V for more than 20 ns, while voltage on the I<sup>2</sup>C bus pins, SCL and SDA, should not exceed the absolute maximum ratings, irrespective of V<sub>CC</sub>.

<sup>3.</sup> A Write Cycle refers to writing a Byte or a Page.

<sup>\*</sup> $V_{CC(min)}$  = 1.6 V for Read operations,  $T_A = -20^{\circ}C$  to +85°C.

Table 5. PIN IMPEDANCE CHARACTERISTICS  $V_{CC} = 1.7 \text{ V to } 5.5 \text{ V}$ ,  $T_A = -40 ^{\circ}\text{C}$  to  $+125 ^{\circ}\text{C}$ , unless otherwise specified.\*)

Symbol	Parameter	Conditions	Max	Units
C <sub>IN</sub> (Note 4)	SDA I/O Pin Capacitance	V <sub>IN</sub> = 0 V	8	pF
C <sub>IN</sub> (Note 4)	Input Capacitance (other pins)	V <sub>IN</sub> = 0 V	6	pF
I <sub>WP</sub> , I <sub>A</sub>	WP Input Current, Address Input	V <sub>IN</sub> < V <sub>IH</sub> , V <sub>CC</sub> = 5.5 V	50	μΑ
(Note 5)	Current (A0, A1, A2)	V <sub>IN</sub> < V <sub>IH</sub> , V <sub>CC</sub> = 3.3 V	35	
		V <sub>IN</sub> < V <sub>IH</sub> , V <sub>CC</sub> = 1.7 V	25	
		V <sub>IN</sub> > V <sub>IH</sub>	2	

<sup>4.</sup> These parameters are tested initially and after a design or process change that affects the parameter according to appropriate AEC-Q100 and JEDEC test methods.

Table 6. A.C. CHARACTERISTICS  $V_{CC} = 1.7 \text{ V to } 5.5 \text{ V}$ ,  $T_A = -40 ^{\circ}\text{C}$  to  $+125 ^{\circ}\text{C}$ , unless otherwise specified.\*) (Note 6)

		Stan	dard	Fa	ast	Fast-	-Plus	
Symbol	Parameter	Min	Max	Min	Max	Min	Max	Units
F <sub>SCL</sub>	Clock Frequency		100		400		1,000	kHz
t <sub>HD:STA</sub>	START Condition Hold Time	4		0.6		0.26		μs
t <sub>LOW</sub>	Low Period of SCL Clock	4.7		1.3		0.50		μs
tHIGH	High Period of SCL Clock	4		0.6		0.26		μs
t <sub>SU:STA</sub>	START Condition Setup Time	4.7		0.6		0.26		μs
t <sub>HD:DAT</sub>	Data In Hold Time	0		0		0		μs
t <sub>SU:DAT</sub>	Data In Setup Time	250		100		50		ns
t <sub>R</sub> (Note 7)	SDA and SCL Rise Time		1,000		300		120	ns
t <sub>F</sub> (Note 7)	SDA and SCL Fall Time		300		300		120	ns
tsu:sto	STOP Condition Setup Time	4		0.6		0.26		μs
t <sub>BUF</sub>	Bus Free Time Between STOP and START	4.7		1.3		0.5		μs
t <sub>AA</sub>	SCL Low to Data Out Valid		3.5		0.9		0.45	μs
t <sub>DH</sub> (Note 7)	Data Out Hold Time	100		100		50		ns
T <sub>i</sub> (Note 7)	Noise Pulse Filtered at SCL and SDA Inputs		50		50		50	ns
t <sub>SU:WP</sub>	WP Setup Time	0		0		0		μS
t <sub>HD:WP</sub>	WP Hold Time	2.5		2.5		1		μs
t <sub>WR</sub>	Write Cycle Time	_	4		4		4	ms
t <sub>PU</sub> (Notes 7, 8)	Power-up to Ready Mode	_	0.35		0.35		0.35	ms

<sup>6.</sup> Test conditions according to "A.C. Test Conditions" table.

### **Table 7. A.C. TEST CONDITIONS**

Input Levels	$0.2 \times V_{CC}$ to $0.8 \times V_{CC}$ for $V_{CC} \ge 2.2 \text{ V}$ $0.15 \times V_{CC}$ to $0.85 \times V_{CC}$ for $V_{CC} < 2.2 \text{ V}$
Input Rise and Fall Times	≤ 50 ns
Input Reference Levels	0.3 x V <sub>CC</sub> , 0.7 x V <sub>CC</sub>
Output Reference Levels	0.3 x V <sub>CC</sub> , 0.7 x V <sub>CC</sub>
Output Load	Current Source: $I_{OL}$ = 6 mA ( $V_{CC}$ $\geq$ 2.2 V); $I_{OL}$ = 2 mA ( $V_{CC}$ < 2.2 V); $C_L$ = 100 pF

<sup>5.</sup> When not driven, the WP, A0, A1 and A2 pins are pulled down to GND internally. For improved noise immunity, the internal pull-down is relatively strong; therefore the external driver must be able to supply the pull-down current when attempting to drive the input HIGH. To conserve power, as the input level exceeds the trip point of the CMOS input buffer (~ 0.5 x V<sub>CC</sub>), the strong pull-down reverts to a weak current source. \* $V_{CC(min)}$  = 1.6 V for Read operations,  $T_A = -20^{\circ}C$  to +85°C.

<sup>7.</sup> Tested initially and after a design or process change that affects this parameter. 8.  $t_{PU}$  is the delay between the time  $V_{CC}$  is stable and the device is ready to accept commands.  ${}^*V_{CC(min)} = 1.6 \text{ V}$  for Read operations,  $T_A = -20 {}^\circ\text{C}$  to  $+85 {}^\circ\text{C}$ .

### Power-On Reset (POR)

Each NV24C04LV incorporates Power-On Reset (POR) circuitry which protects the internal logic against powering up in the wrong state.

A NV24C04LV device will power up into Standby mode after  $V_{CC}$  exceeds the POR trigger level and will power down into Reset mode when  $V_{CC}$  drops below the POR trigger level. This bi–directional POR feature protects the device against 'brown–out' failure following a temporary loss of power.

### **Pin Description**

**SCL**: The Serial Clock input pin accepts the Serial Clock generated by the Master.

**SDA**: The Serial Data I/O pin receives input data and transmits data stored in EEPROM. In transmit mode, this pin is open drain. Data is acquired on the positive edge, and is delivered on the negative edge of SCL.

**A0, A1 and A2**: The Address inputs set the device address when cascading multiple devices. When not driven, these pins are pulled LOW internally.

**WP**: The Write Protect input pin inhibits all write operations, when pulled HIGH. When not driven, this pin is pulled LOW internally.

### **Functional Description**

The NV24C04LV supports the Inter–Integrated Circuit (I<sup>2</sup>C) Bus data transmission protocol, which defines a device that sends data to the bus as a transmitter and a device receiving data as a receiver. Data flow is controlled by a Master device, which generates the serial clock and all START and STOP conditions. The NV24C04LV acts as a Slave device. Master and Slave alternate as either transmitter or receiver.

### I<sup>2</sup>C Bus Protocol

The  $I^2C$  bus consists of two 'wires', SCL and SDA. The two wires are connected to the  $V_{CC}$  supply via pull-up resistors. Master and Slave devices connect to the 2-wire bus via their respective SCL and SDA pins. The transmitting device pulls down the SDA line to 'transmit' a '0' and releases it to 'transmit' a '1'.

Data transfer may be initiated only when the bus is not busy (see AC Characteristics).

During data transfer, the SDA line must remain stable while the SCL line is high. An SDA transition while SCL is high will be interpreted as a START or STOP condition (Figure 2). The START condition precedes all commands. It consists of a HIGH to LOW transition on SDA while SCL is HIGH. The START acts as a 'wake-up' call to all receivers. Absent a START, a Slave will not respond to commands. The STOP condition completes all commands. It consists of a LOW to HIGH transition on SDA while SCL is HIGH.

NOTE: The I/O pins of NV24C04LV do not obstruct the SCL and SDA lines if the VCC supply is switched off. During power-up, the SCL and SDA pins (connected with pull-up resistors to VCC) will follow the VCC monotonically from VSS (0 V) to nominal VCC value, regardless of pull-up resistor value. The delta between the VCC and the instantaneous voltage levels during power ramping will be determined by the relation between bus time constant (determined by pull-up resistance and bus capacitance) and actual VCC ramp rate.

### **Device Addressing**

The Master initiates data transfer by creating a START condition on the bus. The Master then broadcasts an 8-bit serial Slave address. For normal Read/Write operations, the first 4 bits of the Slave address are fixed at 1010 (Ah). The next 3 bits are used as programmable address bits when cascading multiple devices and/or as internal address bits. The last bit of the slave address, R/W, specifies whether a Read (1) or Write (0) operation is to be performed. The 3 address space extension bits are assigned as illustrated in Figure 3.  $A_2$ ,  $A_1$  and  $A_0$  must match the state of the external address pins, and  $a_{10}$ ,  $a_9$  and  $a_8$  are internal address bits.

### Acknowledge

After processing the Slave address, the Slave responds with an acknowledge (ACK) by pulling down the SDA line during the 9th clock cycle (Figure 4). The Slave will also acknowledge the address byte and every data byte presented in Write mode. In Read mode the Slave shifts out a data byte, and then releases the SDA line during the 9th clock cycle. As long as the Master acknowledges the data, the Slave will continue transmitting. The Master terminates the session by not acknowledging the last data byte (NoACK) and by issuing a STOP condition. Bus timing is illustrated in Figure 5.

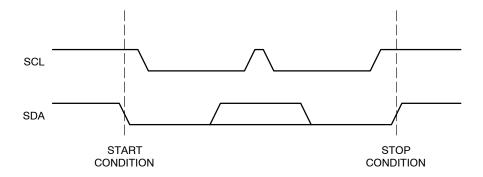


Figure 2. Start/Stop Timing

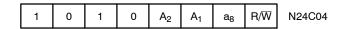


Figure 3. Slave Address Bits

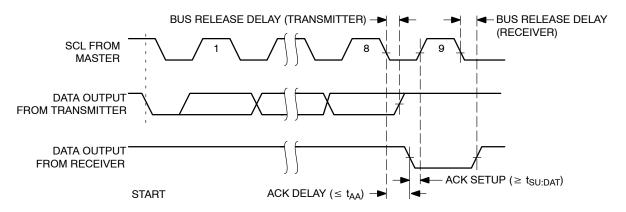


Figure 4. Acknowledge Timing

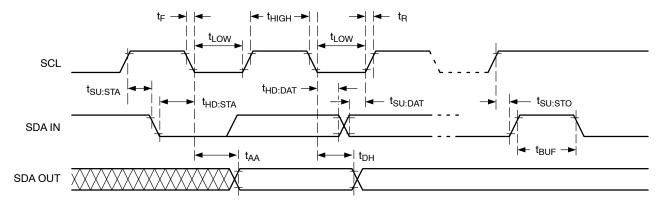


Figure 5. Bus Timing

#### WRITE OPERATIONS

### **Byte Write**

In Byte Write mode, the Master sends the START condition and the Slave address with the R/W bit set to zero to the Slave. After the Slave generates an acknowledge, the Master sends the byte address that is to be written into the address pointer of the NV24C04LV. After receiving another acknowledge from the Slave, the Master transmits the data byte to be written into the addressed memory location. The NV24C04LV device will acknowledge the data byte and the Master generates the STOP condition, at which time the device begins its internal Write cycle to nonvolatile memory (Figure 6). While this internal cycle is in progress (t<sub>WR</sub>), the SDA output will be tri–stated and the NV24C04LV will not respond to any request from the Master device (Figure 7).

### **Page Write**

The NV24C04LV writes up to 16 bytes of data in a single write cycle, using the Page Write operation (Figure 8). The Page Write operation is initiated in the same manner as the Byte Write operation, however instead of terminating after the data byte is transmitted, the Master is allowed to send up to fifteen additional bytes. After each byte has been transmitted the NV24C04LV will respond with an acknowledge and internally increments the four low order address bits. The high order bits that define the page address remain unchanged. If the Master transmits more than sixteen bytes prior to sending the STOP condition, the address counter 'wraps around' to the beginning of page and previously transmitted data will be overwritten. Once all

sixteen bytes are received and the STOP condition has been sent by the Master, the internal Write cycle begins. At this point all received data is written to the NV24C04LV in a single write cycle.

### **Acknowledge Polling**

The acknowledge (ACK) polling routine can be used to take advantage of the typical write cycle time. Once the stop condition is issued to indicate the end of the host's write operation, the NV24C04LV initiates the internal write cycle. The ACK polling can be initiated immediately. This involves issuing the start condition followed by the slave address for a write operation. If the NV24C04LV is still busy with the write operation, NoACK will be returned. If the NV24C04LV has completed the internal write operation, an ACK will be returned and the host can then proceed with the next read or write operation.

### **Hardware Write Protection**

With the WP pin held HIGH, the entire memory is protected against Write operations. If the WP pin is left floating or is grounded, it has no impact on the operation of the NV24C04LV. The state of the WP pin is strobed on the last falling edge of SCL immediately preceding the first data byte (Figure 9). If the WP pin is HIGH during the strobe interval, the NV24C04LV will not acknowledge the data byte and the Write request will be rejected.

### **Delivery State**

The NV24C04LV is shipped erased, i.e., all bytes are FFh.

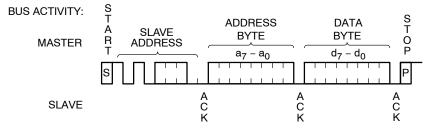


Figure 6. Byte Write Sequence

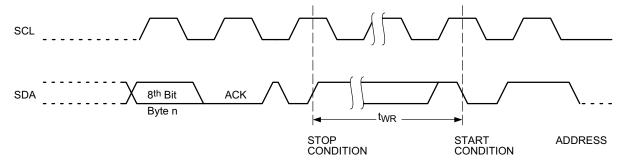


Figure 7. Write Cycle Timing

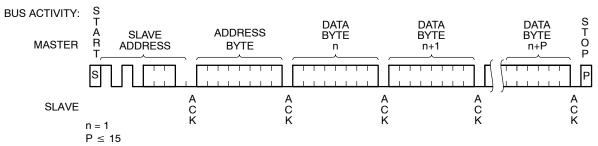


Figure 8. Page Write Sequence

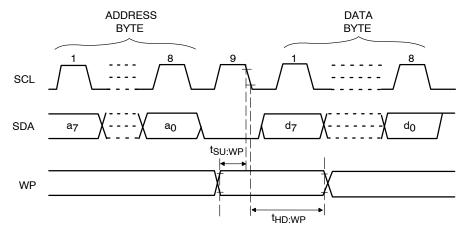


Figure 9. WP Timing

#### **READ OPERATIONS**

#### **Immediate Read**

Upon receiving a Slave address with the R/W bit set to '1', the NV24C04LV will interpret this as a request for data residing at the current byte address in memory. The NV24C04LV will acknowledge the Slave address, will immediately shift out the data residing at the current address, and will then wait for the Master to respond. If the Master does not acknowledge the data (NoACK) and then follows up with a STOP condition (Figure 10), the NV24C04LV returns to Standby mode.

### **Selective Read**

Selective Read operations allow the Master device to select at random any memory location for a read operation. The Master device first performs a 'dummy' write operation by sending the START condition, slave address and byte

address of the location it wishes to read. After the NV24C04LV acknowledges the byte address, the Master device resends the START condition and the slave address, this time with the R/W bit set to one. The NV24C04LV then responds with its acknowledge and sends the requested data byte. The Master device does not acknowledge the data (NoACK) but will generate a STOP condition (Figure 11).

### **Sequential Read**

If during a Read session, the Master acknowledges the 1<sup>st</sup> data byte, then the NV24C04LV will continue transmitting data residing at subsequent locations until the Master responds with a NoACK, followed by a STOP (Figure 12). In contrast to Page Write, during Sequential Read the address count will automatically increment to and then wrap—around at end of memory (rather than end of page).

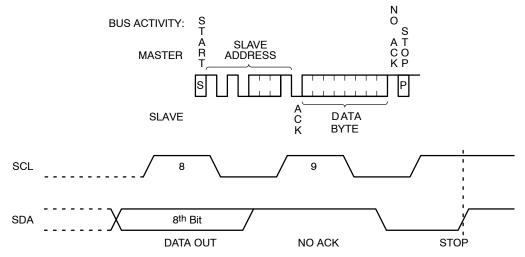


Figure 10. Immediate Read Sequence and Timing

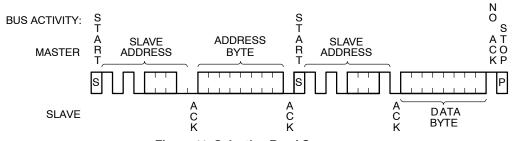


Figure 11. Selective Read Sequence

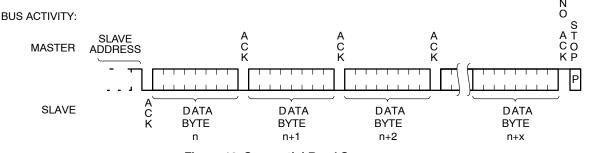
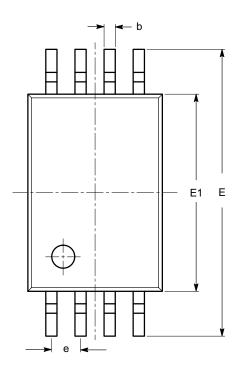


Figure 12. Sequential Read Sequence

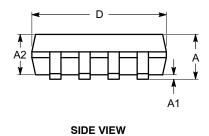
### **PACKAGE DIMENSIONS**

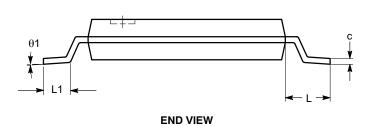
## TSSOP8, 4.4x3 CASE 948AL ISSUE O



SYMBOL	MIN	NOM	MAX
Α			1.20
A1	0.05		0.15
A2	0.80	0.90	1.05
b	0.19		0.30
С	0.09		0.20
D	2.90	3.00	3.10
Е	6.30	6.40	6.50
E1	4.30	4.40	4.50
е	0.65 BSC		
L	1.00 REF		
L1	0.50	0.60	0.75
θ	0°		8°

### **TOP VIEW**





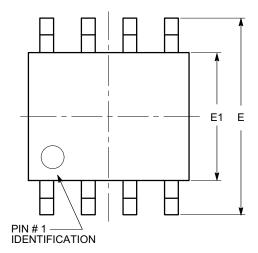
### Notes:

- (1) All dimensions are in millimeters. Angles in degrees.(2) Complies with JEDEC MO-153.

1. ALL DIMENSIONS ARE IN

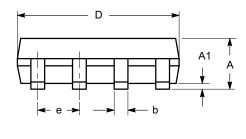
## **PACKAGE DIMENSIONS**

SOIC 8, 150 mils CASE 751BD ISSUE O

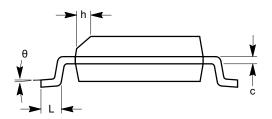


SYMBOL	MIN	NOM	MAX
А	1.35		1.75
A1	0.10		0.25
b	0.33		0.51
С	0.19		0.25
D	4.80		5.00
E	5.80		6.20
E1	3.80		4.00
е		1.27 BSC	
h	0.25		0.50
L	0.40		1.27
θ	0°		8°

**TOP VIEW** 



SIDE VIEW

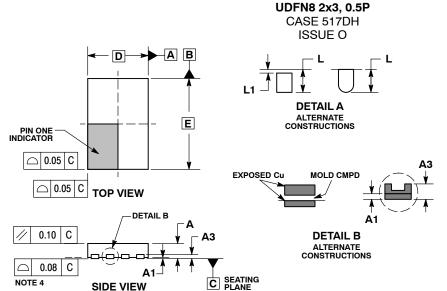


### **END VIEW**

### Notes:

- (1) All dimensions are in millimeters. Angles in degrees.
- (2) Complies with JEDEC MS-012.

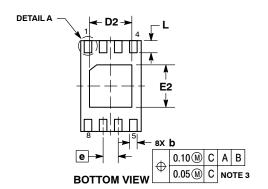
### **PACKAGE DIMENSIONS**



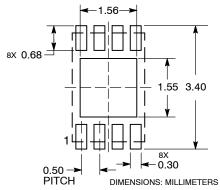
- NOTES:
  1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  2. CONTROLLING DIMENSION: MILLIMETERS.
- CONTROLLING DIMENSION: MILLIMET EAS. DIMENSION 6 APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.15 AND 0.25MM FROM THE TERMINAL TIP. COPLANARITY APPLIES TO THE EXPOSED
- PAD AS WELL AS THE TERMINALS.

  5. FOR DEVICE OPN CONTAINING W OPTION,
- DETAIL B ALTERNATE CONSTRUCTION IS NOT APPLICABLE.

	MILLIMETERS			
DIM	MIN	MAX		
Α	0.45	0.55		
A1	0.00	0.05		
A3	0.13	REF		
b	0.20	0.30		
D	2.00	BSC		
D2	1.30	1.50		
E	3.00	BSC		
E2	1.30	1.50		
е	0.50 BSC			
L	0.30	0.50		
L1		0.15		

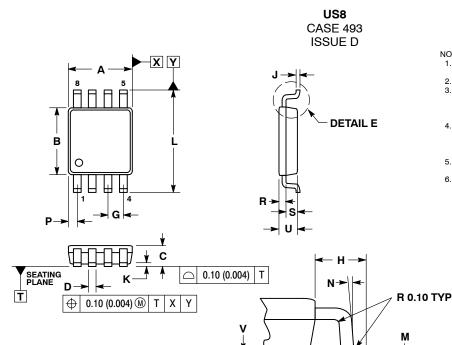


#### **RECOMMENDED SOLDERING FOOTPRINT\***



\*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

### **PACKAGE DIMENSIONS**



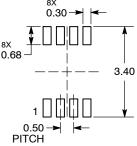
#### NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI
- DIMENSIONING AND TOLEHANCING PER ANSI Y14.5M, 1982.
   CONTROLLING DIMENSION: MILLIMETERS.
   DIMENSION A DOES NOT INCLUDE MOLD FLASH, PROTRUSION OR GATE BURR. MOLD FLASH. PROTRUSION AND GATE BURR SHALL NOT EXCEED 0.14MM (0.0055") PER SIDE.
   DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION, INTERLEAD FLASH AND PROTRUSION SIMPLE NOT EXCEPTED 4.4MM.
- FLASH OH PHOTHUSION. INTERLEAD FLASH AND PROTRUSION SHALL NOT EXCEED 0.14MM (0.0055") PER SIDE. LEAD FINISH IS SOLDER PLATING WITH THICKNESS OF 0.0076-0.0203MM (0.003-0.008"). ALL TOLERANCE UNLESS OTHERWISE SPECIFIED AC
- SPECIFIED ±0.0508MM (0.0002").

	MILLIN	IETERS	INC	HES
DIM	MIN	MAX	MIN	MAX
Α	1.90	2.10	0.075	0.083
В	2.20	2.40	0.087	0.094
С	0.60	0.90	0.024	0.035
D	0.17	0.25	0.007	0.010
F	0.20	0.35	0.008	0.014
G	0.50	BSC	0.020	BSC
Н	0.40	REF	0.016 REF	
J	0.10	0.18	0.004	0.007
K	0.00	0.10	0.000	0.004
L	3.00	3.20	0.118	0.128
М	0 °	6 °	0 °	6°
N	0 °	10 °	0 °	10 °
P	0.23	0.34	0.010	0.013
R	0.23	0.33	0.009	0.013
S	0.37	0.47	0.015	0.019
U	0.60	0.80	0.024	0.031
V	0.12	BSC	0.005	BSC

# RECOMMENDED SOLDERING FOOTPRINT\*

**DETAIL E** 

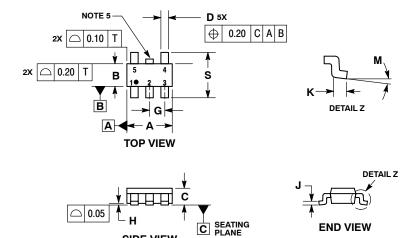


DIMENSIONS: MILLIMETERS

<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### **PACKAGE DIMENSIONS**

### TSOP-5 **CASE 483** ISSUE M



**SIDE VIEW** 

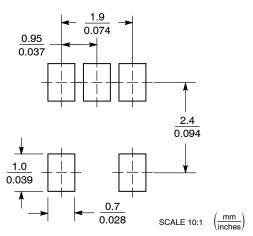
- NOTES:
  1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  2. CONTROLLING DIMENSION: MILLIMETERS.

- CONTROLLING DIMENSION: MILLIMETERS.
  MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH
  THICKNESS. MINIMUM LEAD THICKNESS IS THE
  MINIMUM THICKNESS OF BASE MATERIAL.
  DIMENSIONS A AND B DO NOT INCLUDE MOLD
  FLASH, PROTRUSIONS, OR GATE BURRS. MOLD
  FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT
  EXCEED 0.15 PER SIDE. DIMENSION A.
  OPTIONAL CONSTRUCTION: AN ADDITIONAL
  TRIMMED LEAD IS ALLOWED IN THIS LOCATION.
  TRIMMED LEAD NOT TO EXTEND MORE THAN 0.2
  FROM BODY.

	MILLIMETERS			
DIM	MIN	MAX		
Α	2.85	3.15		
В	1.35	1.65		
С	0.90	1.10		
D	0.25	0.50		
G	0.95	BSC		
Н	0.01	0.10		
J	0.10	0.26		
K	0.20	0.60		
М	0 °	10 °		
S	2.50	3.00		

### **SOLDERING FOOTPRINT\***

**END VIEW** 



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### **ORDERING INFORMATION**

OPN	Density (Kb)	Package Type	Temperature Range	Shipping
NV24C04UVLT2G	4	US-8	V = Automotive Grade 1 (-40°C to +125°C)	Tape & Reel, 2,000 Units / Reel
NV24C04MUW3VLTBG	4	UDFN-8 Wettable Flank	V = Automotive Grade 1 (-40°C to +125°C)	Tape & Reel, 3,000 Units / Reel
NV24C04DWVLT3G	4	SOIC-8	V = Automotive Grade 1 (-40°C to +125°C)	Tape & Reel, 3,000 Units / Reel
NV24C04DTVLT3G	4	TSSOP-8	V = Automotive Grade 1 (-40°C to +125°C)	Tape & Reel, 3,000 Units / Reel
NV24C04SNVLT3G*	4	TSOP-5	V = Automotive Grade 1 (-40°C to +125°C)	Tape & Reel, 3,000 Units / Reel

<sup>9.</sup> All packages are RoHS-compliant (Lead-free, Halogen-free).

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For additional information, please contact your local Sales Representative

<sup>10.</sup> For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

<sup>\*</sup>Product in development.